

Search Notes**Application/Control No.**

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Examiner

John Kreck

**Applicant(s)/Patent under
Reexamination**

CHAN ET AL.

Art Unit

3672

SEARCHED

Class	Subclass	Date	Examiner
588	258,252, 315, 412	6/4/2010	JK

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
text	6/4/2010	JK